

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2037		SERIAL NO. 09/945,508	
OJPE JC10 MAY 29 2002 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT: Kei-Yu Ko			RECEIVED NOV 4 2002 TC 1700
		FILING DATE August 30, 2001			GROUP 1765			
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
LJHE	AA	4,381,201	04/26/83	Sakurai		148	1.5	
LJHE	AB	4,472,729	09/18/84	Shibata et al.		357	49	
LJHE	AC	4,489,478	12/25/84	Sakurai		29	574	
LJHE	AD	4,681,657	07/21/87	Hwang et al.		156	657	
LJHE	AE	4,753,709	06/28/88	Welch et al.		156	643	
LJHE	AF	4,807,016	02/21/89	Douglas		357	67	
LJHE	AG	4,818,335	04/04/89	Karnett		156	644	
LJHE	AH	4,966,865	10/30/90	Welch et al.		437	192	
LJHE	AI	5,037,777	08/06/91	Mele et al.		437	195	
LJHE	AJ	5,063,169	11/05/91	DeBruin et al.		437	41	
LJHE	AK	5,084,417	01/28/92	Joshi et al.		437	192	
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country		Class	Subclass	Translation
LJHE	AL	56-114355	09.08.81	Japan (Yoji)				Yes No
LJHE	AM	60-42821	03.07.85	Japan (Mitsubishi Electric Corp)				Abstract
LJHE	AN	61-133555	12.09.86	Japan (Varta Batterie)				Abstract
LJHE	AO	0 265 584 A2	05.05.87	EPO (IBM)				X
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
LJHE	AP	Abatchev et al., <i>Study of the Boron-Phosphorous Doped and Undoped Silicate Glass Etching in CHF₃/Ar Plasma</i> , 96 ELECTROCHEM SOC. PROCEEDINGS, No. 12, pp. 522-530 (1996).						
LJHE	AQ	Ikegami et al., <i>Mechanisms of High PSG/SiO₂ Selective Etching in a Highly Polymerized Fluorocarbon Plasma</i> , 30 JAP. J. APPL. PHYS., No. 7, pp. 1556-1561 (July 1991).						
EXAMINER Lynette J. Wang-Erwin		DATE CONSIDERED 2/20/2003						
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Kei-Yu Ko			RECEIVED NOV 4 2002 TC 1700	
					FILING DATE August 30, 2001		GROUP 1765		
U.S. PATENT DOCUMENTS									
Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate	
LJME	AA	5,150,276	09/22/92	Gonzalez et al.		361	313		
LJME	AB	5,192,703	03/09/93	Lee et al.		437	52		
LJME	AC	5,208,176	05/04/93	Ahmad et al.		437	47		
LJME	AD	5,210,047	05/11/93	Woo et al.		437	43		
LJME	AE	5,252,517	10/12/93	Blalock et al.		437	195		
LJME	AF	5,286,344	02/15/94	Blalock et al.		156	657		
LJME	AG	5,298,465	03/29/94	Levy		437	225		
LJME	AH	5,312,768	05/17/94	Gonzalez		437	40		
LJME	AI	5,321,286	06/14/94	Koyama et al.		257	315		
LJME	AJ	5,323,047	06/21/94	Nguyen		257	384		
LJME	AK	5,362,666	11/08/94	Dennison		437	52		
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
								Yes No	
LJME	AL	0 465 044 A2	19.06.91	EPO (AT&T)					
LJME	AM	4-345054	12.01.92	Japan (Ricoh Co.)				X	
LJME	AN	0 496 614 A1	23.01.92	EPO (NEC Corp.)					
	AO	4-360570	14.12.92	Japan (Mitsubishi Electric Corp.)				Abstract	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
LJME	AP	van den Hoek et al., <i>Isotropic plasma etching of doped and undoped silicon dioxide for contact holes and vias</i> , 7 J. VAC. SCI. TECHNOL., No. 3, pp. 670-675 (May/June 1989).							
	AQ								
EXAMINER		DATE CONSIDERED							
Dlynnette J. Umz-Eunini		2/20/2003							
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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-2037SERIAL NO.
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APPLICANT: Kei-Yu Ko

FILING DATE
August 30, 2001GROUP
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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
L.J.Y.K	AA	5,366,590	11/22/94	Kadomura	156	662	
L.J.Y.K	AB	5,374,332	12/20/94	Koyama et al.	156	643	
L.J.Y.K	AC	5,401,681	03/28/95	Dennison	437	60	
L.J.Y.K	AD	5,422,308	06/06/95	Nicholls et al.	437	192	
L.J.Y.K	AE	5,423,945	06/13/95	Marks et al.	156	662.1	
L.J.Y.K	AF	5,429,070	07/04/95	Campbell et al.	118	723	
L.J.Y.K	AG	5,445,712	08/29/95	Yanagida	156	662	
L.J.Y.K	AH	5,478,772	12/26/95	Fazan	437	60	
L.J.Y.K	AI	5,482,894	01/09/96	Havemann	437	195	
L.J.Y.K	AJ	5,485,035	01/16/96	Lin et al.	257	637	
L.J.Y.K	AK	5,550,071	08/27/96	Ryou	437	41	

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
L.J.Y.K	AL 5-335482	17.12.93	Japan (Semiconductor Energy)			Abstract	
L.J.Y.K	AM 0 680 084 A1	28.04.95	EPO (Texas Instruments, Inc.)				
L.J.Y.K	AN 0 763 850 A1	30.08.96	EPO (Applied Materials, Inc.)				
L.J.Y.K	AO WO 98/49719	05.11.98	WIPO (Micron Technology, Inc.)				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER *Lynette J. Umz-Eunmi*

DATE CONSIDERED

2/20/2003

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT: Kei-Yu Ko		RECEIVED NOV 4 2002 T-170
		FILING DATE August 30, 2001	GROUP 1765	

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
L.J.M.E.	AA	5,611,888	03/18/97	Bosch et al.	156	643.1	
L.J.M.E.	AB	5,626,716	05/06/97	Bosch et al.	438	723	
L.J.M.E.	AC	5,643,819	07/01/97	Tseng	437	60	
L.J.M.E.	AD	5,677,227	10/14/97	Yang et al.	437	60	
L.J.M.E.	AE	5,685,914	11/11/97	Hills et al.	118	723	
L.J.M.E.	AF	5,685,951	11/11/97	Torek et al.	156	646.1	
L.J.M.E.	AG	5,700,731	12/23/97	Lin et al.	438	381	
L.J.M.E.	AH	5,712,202	01/27/98	Liaw et al.	438	253	
L.J.M.E.	AI	5,731,130	03/24/98	Tseng	430	316	
L.J.M.E.	AJ	5,731,242	03/24/98	Parat et al.	438	586	
L.J.M.E.	AK	5,736,455	04/07/98	Iyer et al.	138	592	

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER <i>Dynotte J. Umeg-Eurnini</i>	DATE CONSIDERED <i>2/20/2003</i>
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT: Kei-Yu Ko				RECEIVED NOV 4 2002 TC 170	
			FILING DATE August 30, 2001		GROUP 1765			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
X.J.YE	AA	5,747,369	05/05/98	Kantimahanti et al.		438	241	
X.J.YE	AB	5,780,338	07/14/98	Jeng et al.		438	253	
X.J.YE	AC	5,783,496	07/21/98	Flanner et al.		438	743	
X.J.YE	AD	5,792,689	08/11/98	Yang et al.		438	253	
X.J.YE	AE	5,792,703	08/11/98	Bronner et al.		438	620	
X.J.YE	AF	5,817,579	10/06/98	Ko et al.		438	740	
X.J.YE	AG	5,821,594	10/13/98	Kasai		257	410	
X.J.YE	AH	5,851,896	12/22/98	Summerfelt		438	396	
X.J.YE	AI	5,871,659	02/16/99	Sakano et al.		216	79	
X.J.YE	AJ	5,883,436	03/16/99	Sadjadi et al.		257	760	
X.J.YE	AK	5,897,352	04/27/99	Lin et al.		438	255	
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country		Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>Lynette J. Yng-Eumin</i>			DATE CONSIDERED <i>2/20/2003</i>					
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U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
L.J.K.E.	AA	5,918,120	06/29/99	Huang	438	239	
L.J.K.E.	AB	5,936,272	08/10/99	Lee	257	306	
L.J.K.E.	AC	5,946,568	08/31/99	Hsiao et al.	438	253	
L.J.K.E.	AD	5,986,299	11/16/99	Nakamura et al.	257	296	
L.J.K.E.	AE	5,990,507	11/23/99	Mochizuki et al.	257	295	
L.J.K.E.	AF	6,074,488	06/13/00	Roderick et al.	118	728	
L.J.K.E.	AG	6,074,958	06/13/00	Tokunaga et al.	438	724	
L.J.K.E.	AH	6,117,788	09/12/00	Ko	438	706	
L.J.K.E.	AI	6,117,791	09/12/00	Ko et al.	438	723	
L.J.K.E.	AJ	6,121,671	09/19/00	Ko et al.	257	644	
L.J.K.E.	AK	6,124,199	09/26/00	Bohr	438	595	

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
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U.S. PATENT DOCUMENTS									
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate	
<i>L.Y.K.</i>	AA	6,153,490	11/28/00	Xing et al.		438	396		
<i>L.Y.K.</i>	AB	6,159,862	12/12/00	Yamada et al.		438	712		
<i>L.Y.K.</i>	AC	6,165,880	12/26/00	Yaung et al.		438	592		
<i>L.Y.K.</i>	AD	6,171,970 B1	01/09/01	Xing et al.		438	706		
<i>L.Y.K.</i>	AE	6,174,451 B1	01/16/01	Hung et al.		216	67		
<i>L.Y.K.</i>	AF	6,183,655 B1	02/06/01	Wang et al.		216	68		
<i>L.Y.K.</i>	AG	6,242,759 B1	06/05/01	Yamazaki et al.		257	69		
<i>L.Y.K.</i>	AH	6,271,542 B1	08/07/01	Emma et al.		257	67		
<i>L.Y.K.</i>	AI	6,277,758 B1	08/21/01	Ko		438	706		
<i>L.Y.K.</i>	AJ	6,337,285 B1	01/08/02	Ko		438	714		
<i>L.Y.K.</i>	AK	6,432,833 B1	08/13/02	Ko		438	714		
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
								Yes	
	AL							No	
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	AN								
	AO								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate
L.J.M.E	AA	6,458,685 B2	10/01/02	Ko et al.		438	621	
L.J.M.E	AB	08/846,671		Ko (as filed and as amended)				04/30/1997
L.J.M.E	AC	09/532,088		Ko (as filed)				03/21/2000
L.J.M.E	AD	09/579,402		Ko (as filed and as amended)				05/25/2000
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country		Class	Subclass	Translation
	AL							Yes
	AM							No
	AN							
	AO							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AP							
	AQ							
EXAMINER: <i>Lynette T. King-Evans</i>		DATE CONSIDERED 2/20/2003						
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